Search	Notes	(continue	d)
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Application/Control No.	Applicant(s)/Patent under Reexamination	
10/644,025	CHANG, SHUN-CHEN	
Examiner	Art Unit	
Dwayne J. White	3745	

SEARCHED			
Class	Subclass	Date	Examiner
updated		12/17/2004	DJW
updated		4/28/2005	DJW
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INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
See	printout	9/16/2005	DJW
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
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Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/644,025	CHANG, SHUN-	CHEN
Examiner	Art Unit	
Dwayne J. White	3745	

	SEARCHED				
Class	Subclass	Date	Examiner		
415	191				
	192				
	193				
	185				
	121.2				
	199.4				
	199.5				
	208.2				
	209.1				
	211.2				
	215.1				
	223				
361	695				
	697				

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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SEARCH NO (INCLUDING SEARCH)
	DATE	EXMR
Search Updated from Parent case	7/22/2004	DJW
East text Search	7/22/2005	DJW